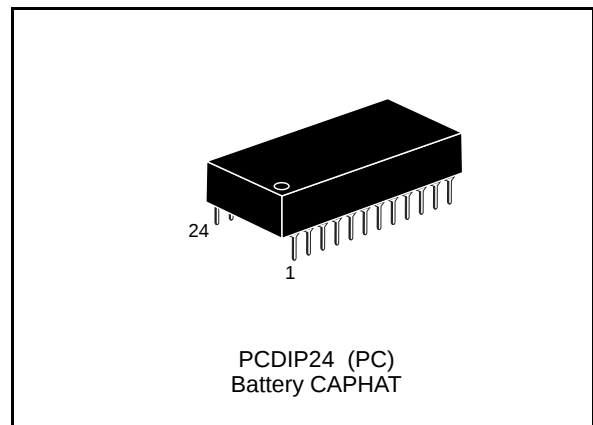




M48Z02 M48Z12

16 Kbit (2Kb x 8) ZEROPOWER® SRAM

- INTEGRATED ULTRA LOW POWER SRAM, POWER-FAIL CONTROL CIRCUIT and BATTERY
- UNLIMITED WRITE CYCLES
- READ CYCLE TIME EQUALS WRITE CYCLE TIME
- AUTOMATIC POWER-FAIL CHIP DESELECT and WRITE PROTECTION
- WRITE PROTECT VOLTAGES (V_{PFD} = Power-fail Deselect Voltage):
 - M48Z02: $4.50V \leq V_{PFD} \leq 4.75V$
 - M48Z12: $4.20V \leq V_{PFD} \leq 4.50V$
- SELF-CONTAINED BATTERY in the CAPHAT DIP PACKAGE
- PIN and FUNCTION COMPATIBLE with JEDEC STANDARD 2K x 8 SRAMS



DESCRIPTION

The M48Z02/12 ZEROPOWER® RAM is a 2K x 8 non-volatile static RAM which is pin and functional compatible with the DS1220.

A special 24 pin 600mil DIP CAPHAT™ package houses the M48Z02/12 silicon with a long life lithium button cell to form a highly integrated battery backed-up memory solution.

The M48Z02/12 button cell has sufficient capacity and storage life to maintain data and clock functionality for an accumulated time period of at least 10 years in the absence of power over the operating temperature range.

Table 1. Signal Names

A0-A10	Address Inputs
DQ0-DQ7	Data Inputs / Outputs
$\bar{E}$	Chip Enable
$\bar{G}$	Output Enable
$\bar{W}$	Write Enable
V_{CC}	Supply Voltage
V_{SS}	Ground

Figure 1. Logic Diagram

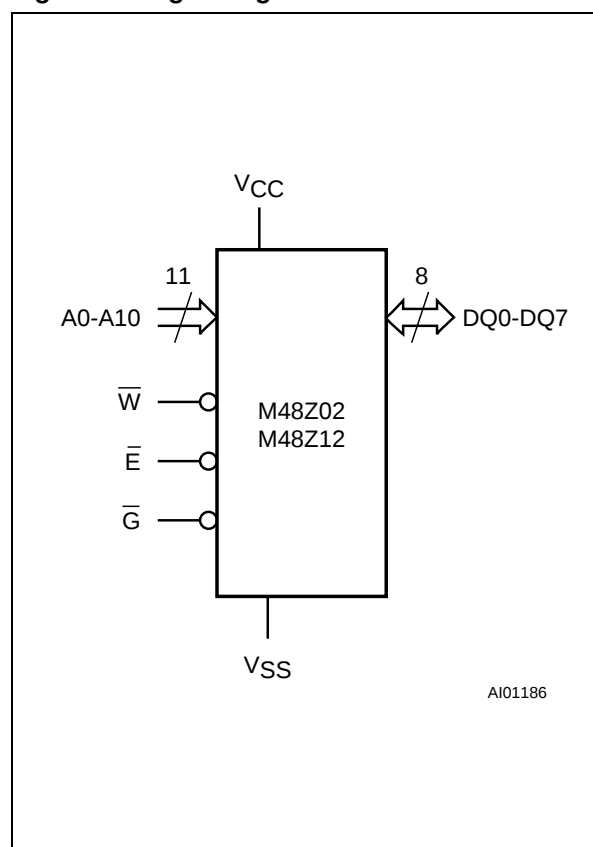


Table 2. Absolute Maximum Ratings ⁽¹⁾

Symbol	Parameter	Value	Unit
T _A	Ambient Operating Temperature	–40 to 85	°C
T _{STG}	Storage Temperature (V _{CC} Off)	–40 to 85	°C
T _{SLD} ⁽²⁾	Lead Solder Temperature for 10 seconds	260	°C
V _{IO}	Input or Output Voltages	–0.3 to 7	V
V _{CC}	Supply Voltage	–0.3 to 7	V
I _O	Output Current	20	mA
P _D	Power Dissipation	1	W

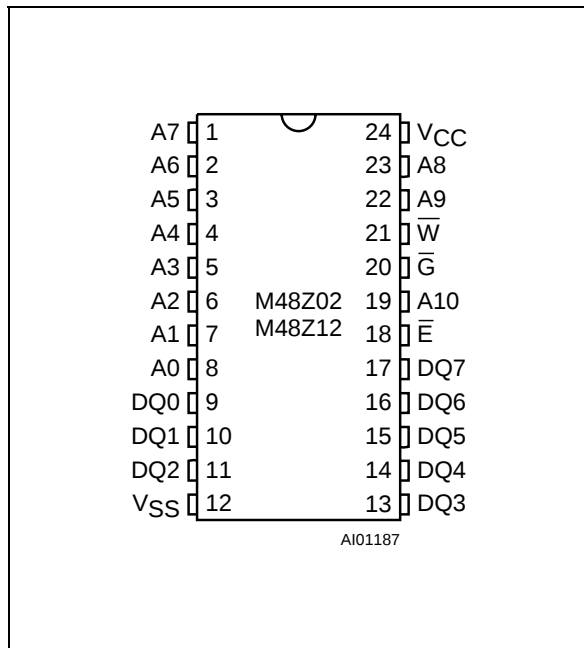
Notes: 1. Stresses greater than those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational section of this specification is not implied. Exposure to the absolute maximum rating conditions for extended periods of time may affect reliability.
2. Soldering temperature not to exceed 260°C for 10 seconds (total thermal budget not to exceed 150°C for longer than 30 seconds).
CAUTION: Negative undershoots below –0.3 volts are not allowed on any pin while in the Battery Back-up mode.

Table 3. Operating Modes

Mode	V _{CC}	$\bar{E}$	$\bar{G}$	$\bar{W}$	DQ0-DQ7	Power
Deselect	4.75V to 5.5V or 4.5V to 5.5V	V _{IH}	X	X	High Z	Standby
Write		V _{IL}	X	V _{IL}	D _{IN}	Active
Read		V _{IL}	V _{IL}	V _{IH}	D _{OUT}	Active
Read		V _{IL}	V _{IH}	V _{IH}	High Z	Active
Deselect	V _{SO} to V _{PFD} (min)	X	X	X	High Z	CMOS Standby
Deselect	≤ V _{SO}	X	X	X	High Z	Battery Back-up Mode

Notes: X = V_{IH} or V_{IL}; V_{SO} = Battery Back-up Switchover Voltage.

Figure 2. DIP Pin Connections

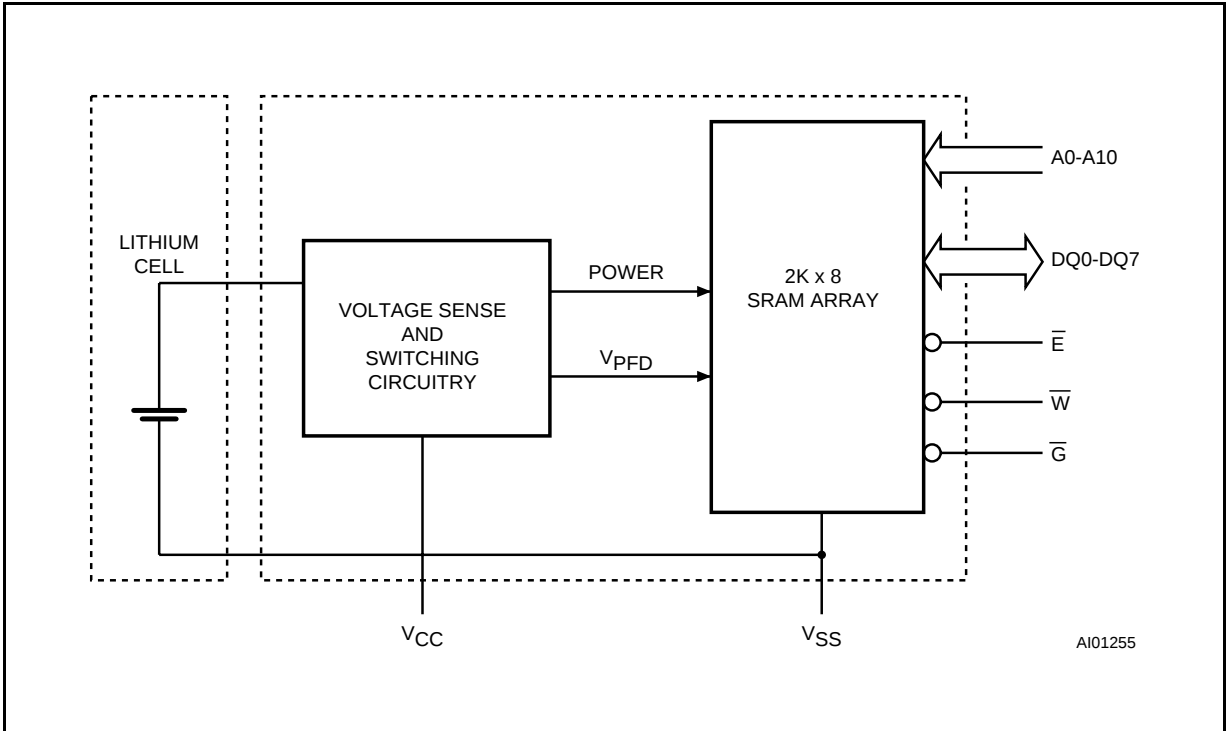


DESCRIPTION (cont'd)

The M48Z02/12 is a non-volatile pin and function equivalent to any JEDEC standard 2K x 8 SRAM. It also easily fits into many ROM, EPROM, and EEPROM sockets, providing the non-volatility of PROMs without any requirement for special write timing or limitations on the number of writes that can be performed.

The M48Z02/12 also has its own Power-fail Detect circuit. The control circuitry constantly monitors the single 5V supply for an out of tolerance condition. When V_{CC} is out of tolerance, the circuit write protects the SRAM, providing a high degree of data security in the midst of unpredictable system operation brought on by low V_{CC}. As V_{CC} falls below approximately 3V, the control circuitry connects the battery which maintains data and clock operation until valid power returns.

Figure 3. Block Diagram



READ MODE

The M48Z02/12 is in the Read Mode whenever $\overline{W}$ (Write Enable) is high and $\overline{E}$ (Chip Enable) is low. The device architecture allows ripple-through access of data from eight of 16,384 locations in the static storage array. Thus, the unique address specified by the 11 Address Inputs defines which one of the 2,048 bytes of data is to be accessed. Valid data will be available at the Data I/O pins within Address Access time (t_{AVQV}) after the last address input signal is stable, providing that the $\overline{E}$ and $\overline{G}$ access times are also satisfied. If the $\overline{E}$ and $\overline{G}$ access times are not met, valid data will be available after the latter of the Chip Enable Access time (t_{ELQV}) or Output Enable Access time (t_{GLQV}).

The state of the eight three-state Data I/O signals is controlled by $\overline{E}$ and $\overline{G}$. If the outputs are activated before t_{AVQV} , the data lines will be driven to an indeterminate state until t_{AVQV} . If the Address Inputs are changed while $\overline{E}$ and $\overline{G}$ remain active, output data will remain valid for Output Data Hold time (t_{AXQX}) but will go indeterminate until the next Address Access.

Table 4. AC Measurement Conditions

Input Rise and Fall Times	$\leq 5\text{ns}$
Input Pulse Voltages	0V to 3V
Input and Output Timing Ref. Voltages	1.5V

Note that Output Hi-Z is defined as the point where data is no longer driven.

Figure 4. AC Testing Load Circuit

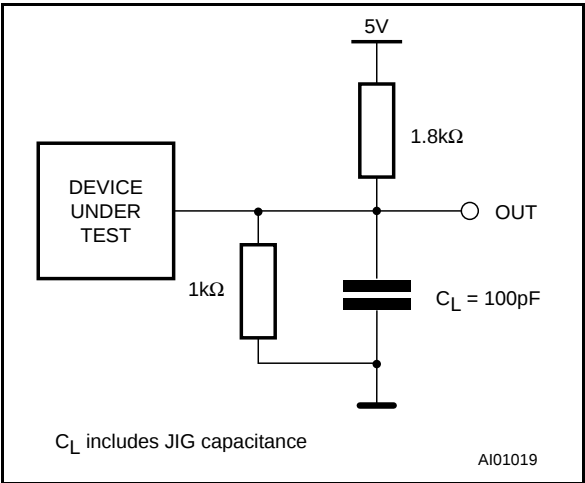


Table 5. Capacitance ⁽¹⁾
(T_A = 25 °C)

Symbol	Parameter	Test Condition	Min	Max	Unit
C _{IN}	Input Capacitance	V _{IN} = 0V		10	pF
C _{IO} ⁽²⁾	Input / Output Capacitance	V _{OUT} = 0V		10	pF

Notes: 1. Effective capacitance measured with power supply at 5V.
2. Outputs deselected

Table 6. DC Characteristics

(T_A = 0 to 70°C or –40 to 85°C; V_{CC} = 4.75V to 5.5V or 4.5V to 5.5V)

Symbol	Parameter	Test Condition	Min	Max	Unit
I _{LI} ⁽¹⁾	Input Leakage Current	0V ≤ V _{IN} ≤ V _{CC}		±1	μA
I _{LO} ⁽¹⁾	Output Leakage Current	0V ≤ V _{OUT} ≤ V _{CC}		±5	μA
I _{CC}	Supply Current	Outputs open		80	mA
I _{CC1}	Supply Current (Standby) TTL	$\bar{E} = V_{IH}$		3	mA
I _{CC2}	Supply Current (Standby) CMOS	$\bar{E} = V_{CC} - 0.2V$		3	mA
V _{IL} ⁽²⁾	Input Low Voltage		–0.3	0.8	V
V _{IH}	Input High Voltage		2.2	V _{CC} + 0.3	V
V _{OL}	Output Low Voltage	I _{OL} = 2.1mA		0.4	V
V _{OH}	Output High Voltage	I _{OH} = –1mA	2.4		V

Notes: 1. Outputs Deselected.
2. Negative spikes of –1V allowed for up to 10ns once per cycle.

Table 7. Power Down/Up Trip Points DC Characteristics ⁽¹⁾
(T_A = 0 to 70°C or –40 to 85°C)

Symbol	Parameter	Min	Typ	Max	Unit
V _{PFD}	Power-fail Deselect Voltage (M48Z02)	4.5	4.6	4.75	V
V _{PFD}	Power-fail Deselect Voltage (M48Z12)	4.2	4.3	4.5	V
V _{SO}	Battery Back-up Switchover Voltage		3.0		V
t _{DR}	Expected Data Retention Time	10			YEARS

Note: 1. All voltages referenced to V_{SS}.

Table 8. Power Down/Up Mode AC Characteristics
 ($T_A = 0$ to 70°C or -40 to 85°C)

Symbol	Parameter	Min	Max	Unit
t_{PD}	$\overline{E}$ or $\overline{W}$ at V_{IH} before Power Down	0		μs
$t_F^{(1)}$	$V_{PFD}(\text{max})$ to $V_{PFD}(\text{min})$ V_{CC} Fall Time	300		μs
$t_{FB}^{(2)}$	$V_{PFD}(\text{min})$ to V_{SO} V_{CC} Fall Time	10		μs
t_R	$V_{PFD}(\text{min})$ to $V_{PFD}(\text{max})$ V_{CC} Rise Time	0		μs
t_{RB}	V_{SO} to $V_{PFD}(\text{min})$ V_{CC} Rise Time	1		μs
t_{REC}	$\overline{E}$ or $\overline{W}$ at V_{IH} after Power Up	2		ms

Notes: 1. $V_{PFD}(\text{max})$ to $V_{PFD}(\text{min})$ fall time of less than t_F may result in deselection/write protection not occurring until $50\text{ }\mu\text{s}$ after V_{CC} passes $V_{PFD}(\text{min})$.
 2. $V_{PFD}(\text{min})$ to V_{SO} fall time of less than t_{FB} may cause corruption of RAM data.

Figure 5. Power Down/Up Mode AC Waveforms

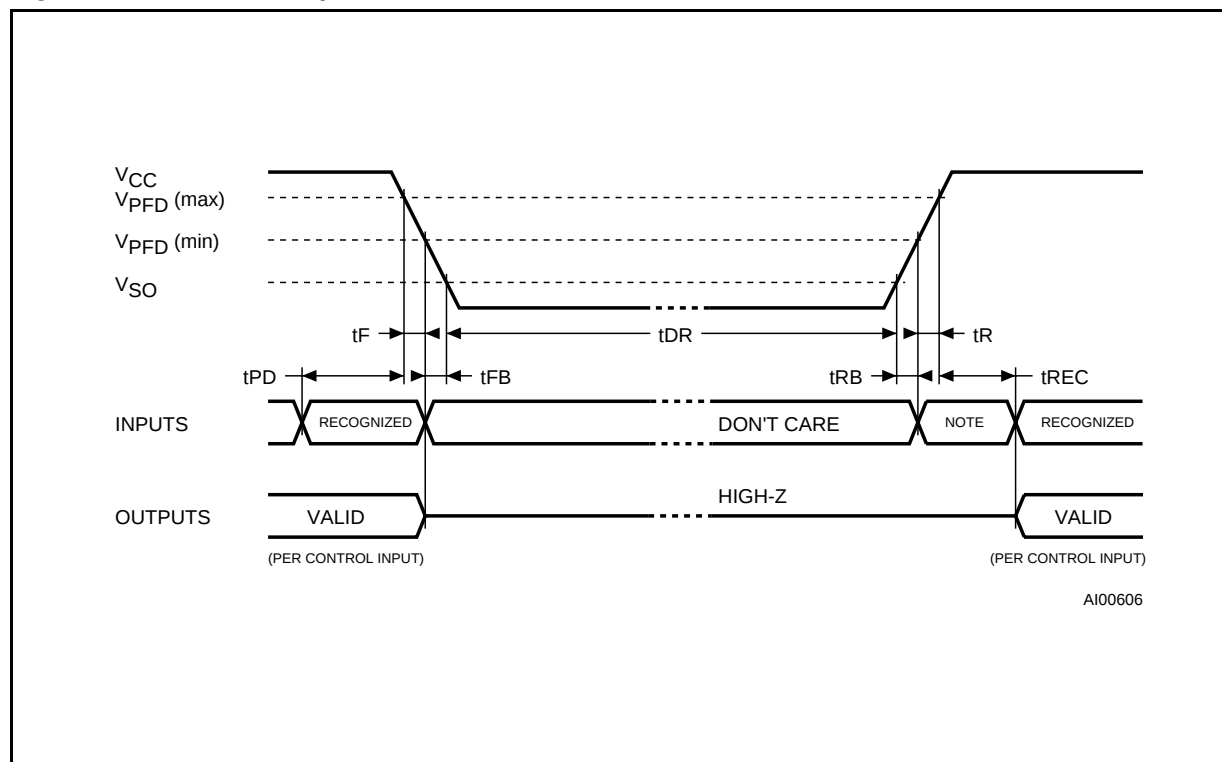


Table 9. Read Mode AC Characteristics(T_A = 0 to 70°C or –40 to 85°C; V_{CC} = 4.75V to 5.5V or 4.5V to 5.5V)

Symbol	Parameter	M48Z02 / M48Z12						Unit
		-70		-150		-200		
		Min	Max	Min	Max	Min	Max	
t _{AVAV}	Read Cycle Time	70		150		200		ns
t _{AVQV}	Address Valid to Output Valid		70		150		200	ns
t _{ELQV}	Chip Enable Low to Output Valid		70		150		200	ns
t _{GLQV}	Output Enable Low to Output Valid		35		75		80	ns
t _{ELQX}	Chip Enable Low to Output Transition	5		10		10		ns
t _{GLQX}	Output Enable Low to Output Transition	5		5		5		ns
t _{EHQZ}	Chip Enable High to Output Hi-Z		25		35		40	ns
t _{GHQZ}	Output Enable High to Output Hi-Z		25		35		40	ns
t _{AXQX}	Address Transition to Output Transition	10		5		5		ns

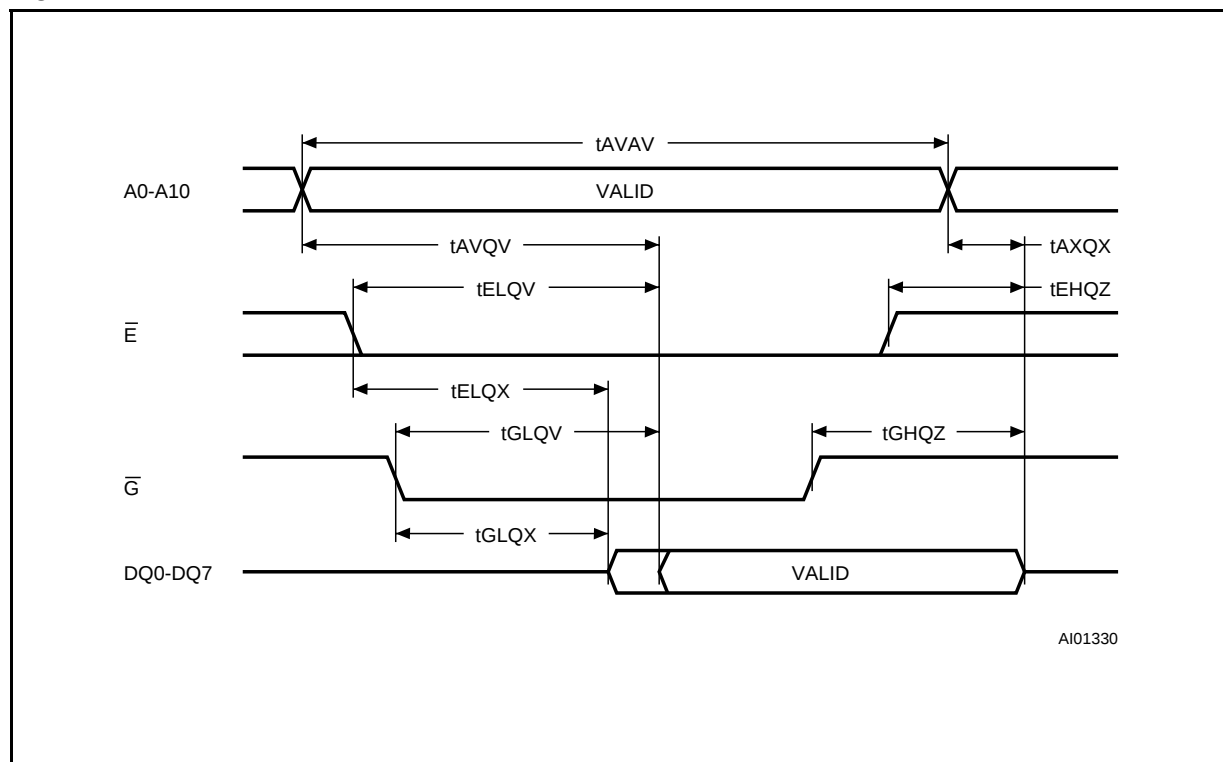
Figure 6. Read Mode AC Waveforms**Note:** Write Enable ($\bar{W}$) = High.

Table 10. Write Mode AC Characteristics(T_A = 0 to 70°C or –40 to 85°C; V_{CC} = 4.75V to 5.5V or 4.5V to 5.5V)

Symbol	Parameter	M48Z02 / M48Z12						Unit
		-70		-150		-200		
		Min	Max	Min	Max	Min	Max	
t _{AVAV}	Write Cycle Time	70		150		200		ns
t _{AVWL}	Address Valid to Write Enable Low	0		0		0		ns
t _{AVEL}	Address Valid to Chip Enable Low	0		0		0		ns
t _{WLWH}	Write Enable Pulse Width	50		90		120		ns
t _{LELH}	Chip Enable Low to Chip Enable High	55		90		120		ns
t _{WHAX}	Write Enable High to Address Transition	0		10		10		ns
t _{EHAX}	Chip Enable High to Address Transition	0		10		10		ns
t _{DVWH}	Input Valid to Write Enable High	30		40		60		ns
t _{DVEH}	Input Valid to Chip Enable High	30		40		60		ns
t _{WHDX}	Write Enable High to Input Transition	5		5		5		ns
t _{EHDX}	Chip Enable High to Input Transition	5		5		5		ns
t _{WLQZ}	Write Enable Low to Output Hi-Z		25		50		60	ns
t _{AVWH}	Address Valid to Write Enable High	60		120		140		ns
t _{AVEH}	Address Valid to Chip Enable High	60		120		140		ns
t _{WHQX}	Write Enable High to Output Transition	5		10		10		ns

WRITE MODE

The M48Z02/12 is in the Write Mode whenever $\overline{W}$ and $\overline{E}$ are active. The start of a write is referenced from the latter occurring falling edge of $\overline{W}$ or $\overline{E}$. A write is terminated by the earlier rising edge of $\overline{W}$ or $\overline{E}$. The addresses must be held valid throughout the cycle. $\overline{E}$ or $\overline{W}$ must return high for a minimum

of t_{EHAX} from Chip Enable or t_{WHAX} from Write Enable prior to the initiation of another read or write cycle. Data-in must be valid t_{DVWH} prior to the end of write and remain valid for t_{WHDX} afterward. $\overline{G}$ should be kept high during write cycles to avoid bus contention; although, if the output bus has been activated by a low on $\overline{E}$ and $\overline{G}$, a low on $\overline{W}$ will disable the outputs t_{WLQZ} after $\overline{W}$ falls.

Figure 7. Write Enable Controlled, Write AC Waveforms

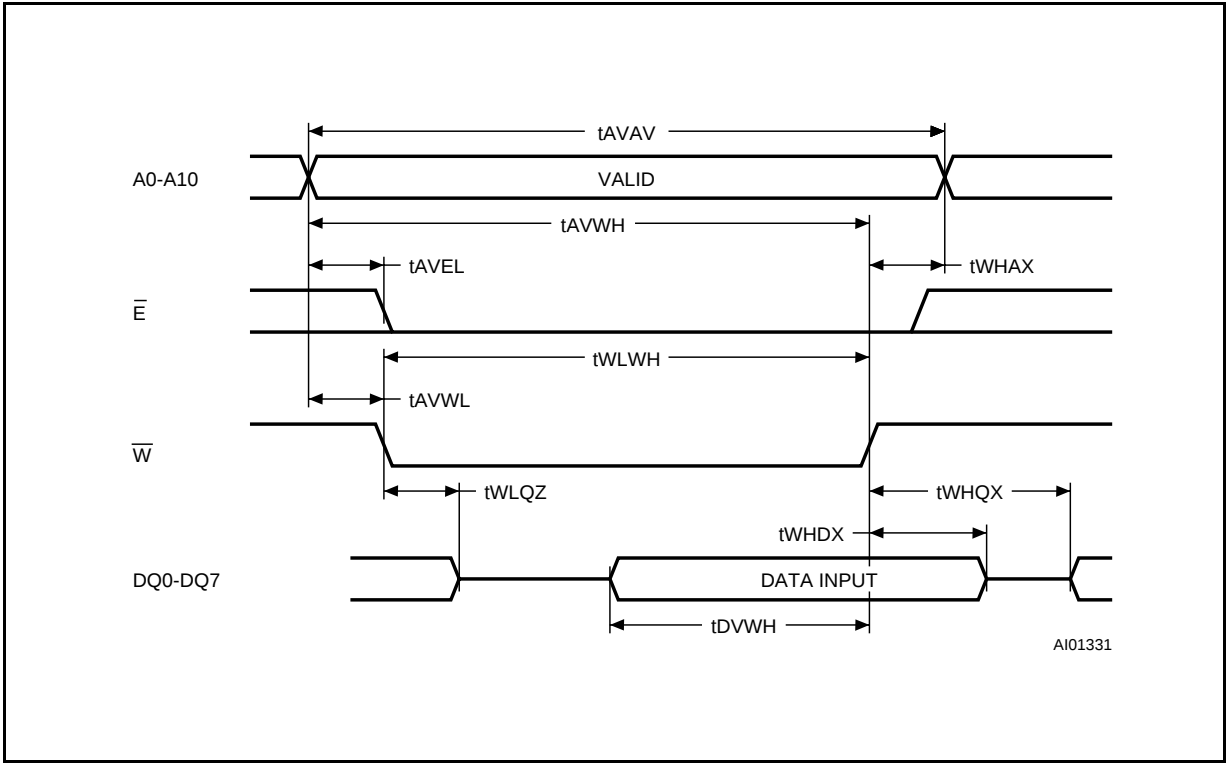
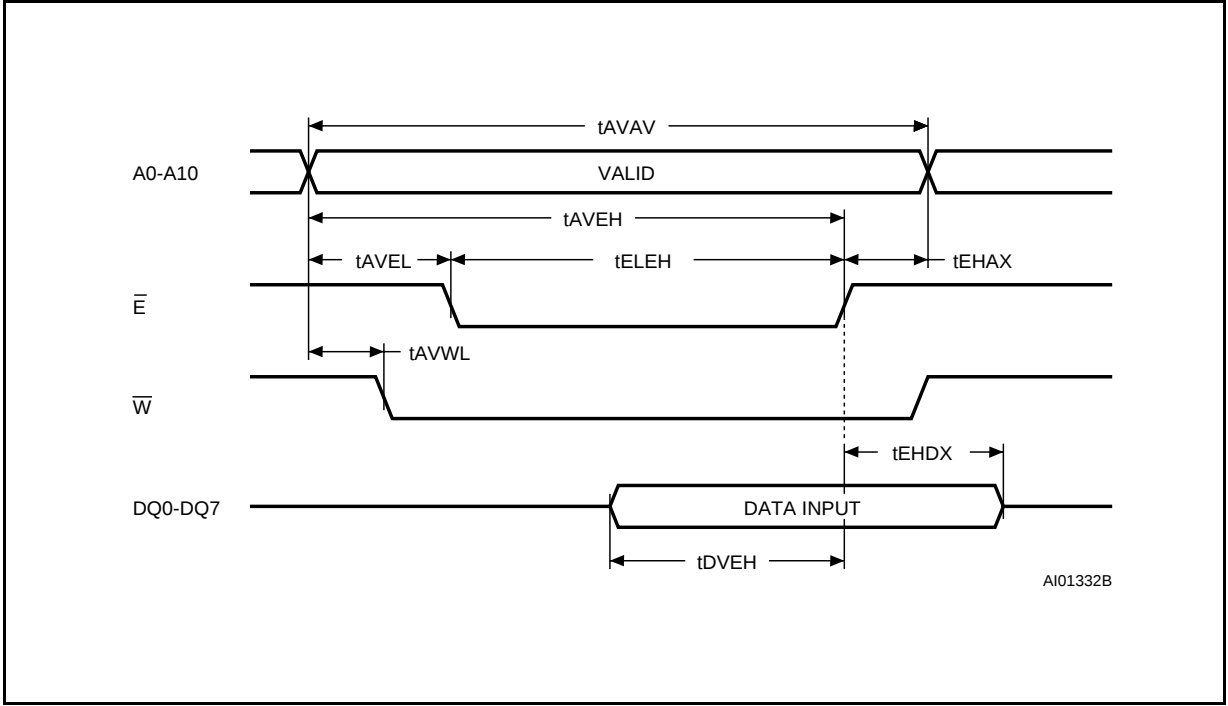


Figure 8. Chip Enable Controlled, Write AC Waveforms



DATA RETENTION MODE

With valid V_{CC} applied, the M48Z02/12 operates as a conventional BYTEWIDE™ static RAM. Should the supply voltage decay, the RAM will automatically power-fail deselect, write protecting itself when V_{CC} falls within the $V_{PFD(max)}$, $V_{PFD(min)}$ window. All outputs become high impedance, and all inputs are treated as "don't care."

Note: A power failure during a write cycle may corrupt data at the currently addressed location, but does not jeopardize the rest of the RAM's content. At voltages below $V_{PFD(min)}$, the user can be assured the memory will be in a write protected state, provided the V_{CC} fall time is not less than t_F . The M48Z02/12 may respond to transient noise spikes on V_{CC} that reach into the deselect window during the time the device is sampling V_{CC} . Therefore, decoupling of the power supply lines is recommended.

The power switching circuit connects external V_{CC} to the RAM and disconnects the battery when V_{CC} rises above V_{SO} . As V_{CC} rises, the battery voltage is checked. If the voltage is too low, an internal Battery Not OK ($\overline{BOK}$) flag will be set. The $\overline{BOK}$ flag can be checked after power up. If the $\overline{BOK}$ flag is set, the first write attempted will be blocked. The flag is automatically cleared after the first write, and normal RAM operation resumes. Figure 9 illustrates how a $\overline{BOK}$ check routine could be structured.

POWER SUPPLY DECOUPLING and UNDER-SHOOT PROTECTION

I_{CC} transients, including those produced by output switching, can produce voltage fluctuations, resulting in spikes on the V_{CC} bus. These transients can be reduced if capacitors are used to store energy, which stabilizes the V_{CC} bus. The energy stored in the bypass capacitors will be released as low going spikes are generated or energy will be absorbed when overshoots occur. A ceramic bypass capacitor value of $0.1\mu F$ (as shown in Figure 10) is recommended in order to provide the needed filtering.

In addition to transients that are caused by normal SRAM operation, power cycling can generate negative voltage spikes on V_{CC} that drive it to values below V_{SS} by as much as one Volt. These negative spikes can cause data corruption in the SRAM while in battery backup mode. To protect from these voltage spikes, it is recommended to connect a schottky diode from V_{CC} to V_{SS} (cathode connected to V_{CC} , anode to V_{SS}). Schottky diode 1N5817 is recommended for through hole and MBR5120T3 is recommended for surface mount.

Figure 9. Checking the $\overline{BOK}$ Flag Status

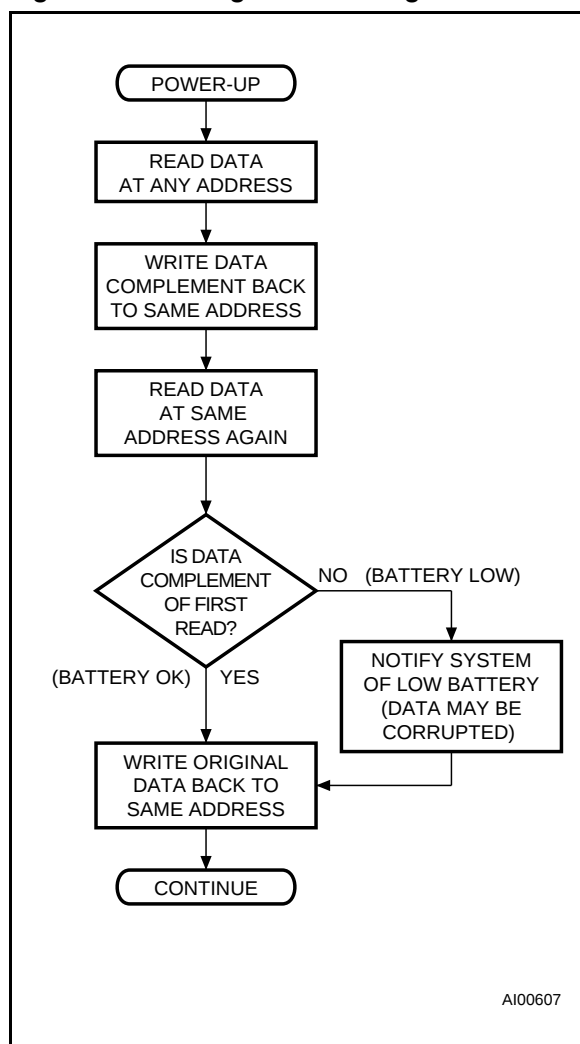
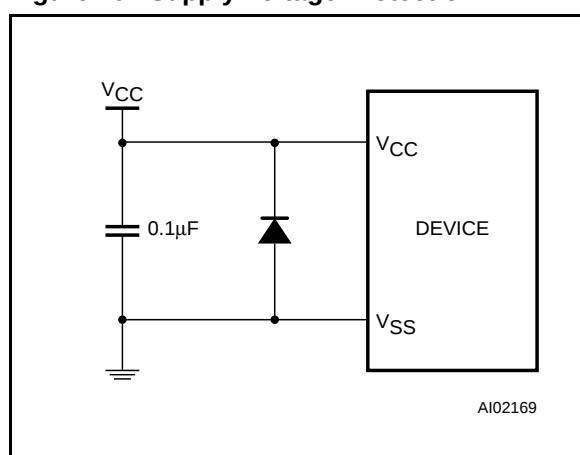
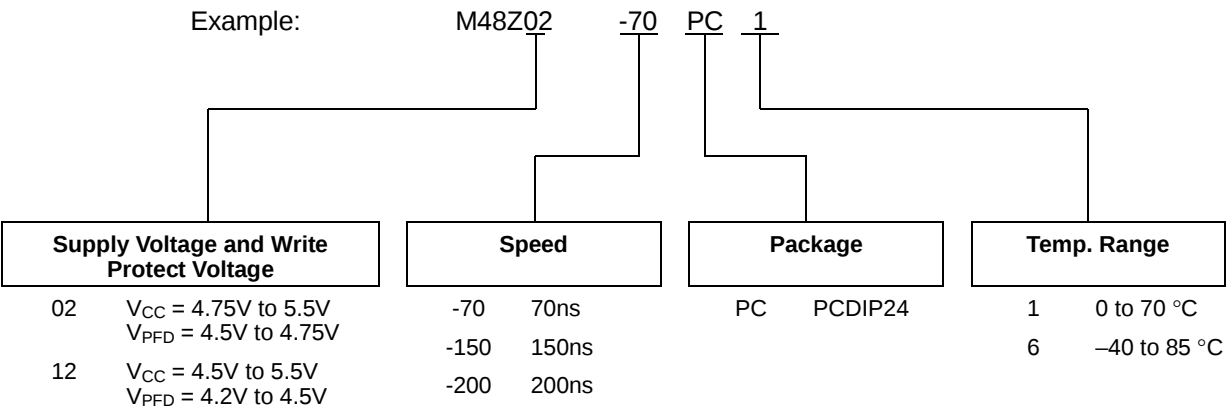


Figure 10. Supply Voltage Protection



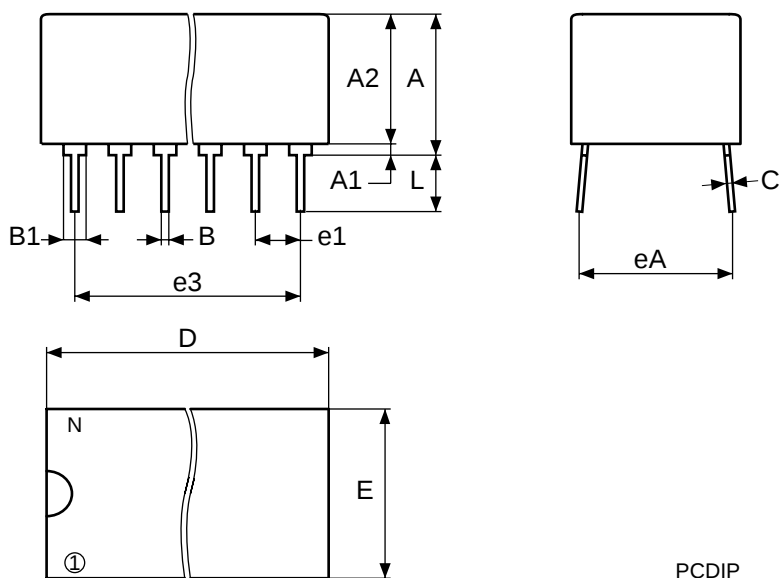
ORDERING INFORMATION SCHEME



For a list of available options (Speed, Package, etc...) or for further information on any aspect of this device, please contact the STMicroelectronics Sales Office nearest to you.

PCDIP24 - 24 pin Plastic DIP, battery CAPHAT

Symb	mm			inches		
	Typ	Min	Max	Typ	Min	Max
A		8.89	9.65		0.350	0.380
A1		0.38	0.76		0.015	0.030
A2		8.38	8.89		0.330	0.350
B		0.38	0.53		0.015	0.021
B1		1.14	1.78		0.045	0.070
C		0.20	0.31		0.008	0.012
D		34.29	34.80		1.350	1.370
E		17.83	18.34		0.702	0.722
e1		2.29	2.79		0.090	0.110
e3		25.15	30.73		0.990	1.210
eA		15.24	16.00		0.600	0.630
L		3.05	3.81		0.120	0.150
N		24			24	



Drawing is not to scale.

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